Application Research Using AI, IoT, HCI, and Big Data Technologies

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Message from the Guest Editors

Recently, AI, big data, IoT, and HCI technologies have been used throughout the industry as core technologies of the Fourth Industrial Revolution. Many researchers are attempting to create a convergence with the latest technology in order to achieve innovative improvements in existing industries. This Special Issue aims to publish various research materials on convergence and application technologies based on AI, machine learning, deep learning, computer vision, big data, IoT, and HCI.

- AI technologies, models, algorithms;

- Deep learning, machine learning, pattern recognition;

- Deep learning-based industrial application research;

- Data science, data mining;

- Applications and platforms using AI and big data;

- Tools and systems for big data;

- Smart computing and edge computing;

- IoT, AIoT, and various sensor data processing and application;

- Technology and application using HCI and AI.

Special Issue

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Message from the Editor-in-Chief

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